



SHEET 1 OF 3

INFORMATION DISCLOSURE
CITATION IN AN
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.
043888-0267

SERIAL NO.
10/629,815

APPLICANT
Tsutomu OHZUKU, et al.

FILING DATE
July 30, 2003

GROUP
1745

U.S. PATENT DOCUMENTS

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EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
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STATEMENT BY APPLICANT**

(Substitute for form 1449/PTO)

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Ch		JP 2003-221236	08-05-2003	HITACHI MAXELL LTD	Corresponds to US 2004/0110063 A1	X

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Ch		Japanese Office Action, issued in Japanese Patent Application No. 2002-303294, dated on September 21, 2007

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